

om PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
MI22-1680SERIAL NO.  
09/875,664LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)

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PATENT & TRADEMARK OFFICEAPPLICANT  
Micron Technology, Inc.FILING DATE  
April 3, 2001GROUP  
7858

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VN	AA	3,886,863	3/23/1999	Nagasaki et al.			
	AB						
	AC						
	AD						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AE						
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EXAMINER <i>rvh Nguye</i>				DATE CONSIDERED <i>03/12/04</i>			

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1680		SERIAL NO. 09/823,664	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT David R. Hembree		FILING DATE April 3, 2001	
				GROUP 2838			
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VN	AA	3,440,407	4/22/69	Goltsos et al.			
	AB	3,614,343	10/19/71	Quinn			
	AC	3,683,306	8/8/72	Bulthuis et al.			
	AD	4,332,081	6/1/82	Francis			
	AE	4,318,944	3/21/83	Faris			
	AF	4,703,555	11/3/87	Hubner			
	AG	5,141,334	8/23/92	Castles			
	AH	5,347,869	9/20/94	Shie et al.			
	AI	5,406,109	4/11/95	Whitney			
	AJ	5,436,646	7/25/95	McArthur et al.			
	AK	5,446,437	8/29/95	Bentien et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
VN	AL	2336778	7/1977	France			
VN	AM	56-12521	2/1981	Kobayashi, Japan			
VN	AN	2-268462	11-1990	Yamanishi, Japan			
	AO						
	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
VN	AR	✓	Application On-Chip Temperature Sensors, Willow Electrical Manufacturing Company Catalog, pp. 773-778, 1992/1993.				
VN	AS	✓	In-Situ Survey System of Resistive and Thermoelectric Properties of Either Pure or Mixed Materials in Thin Films Evaporated Under Ultra High Vacuum, Schavallier, LeBaron, Richon, Serrus, & Gossels, J. Phys. III France, Vol. 2, pp. 409-416, 04/93 (Abstract only).				
VN	AT	✓	Temperature Metrology for CD Control in DUV Lithography, Jeffrey Parker and Wayne Reichen, pp. 111-112, 114, 116, 09/17/97.				
EXAMINER <i>mark Nguy</i>				DATE CONSIDERED 03/12/04			

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE <div style="border: 1px solid black; border-radius: 50%; width: 100px; height: 100px; display: flex; align-items: center; justify-content: center; margin: 0 auto;"> <div style="writing-mode: vertical-rl; transform: rotate(180deg);">PATENT &amp; TRADEMARK OFFICE</div> <div style="text-align: center;">MAY 10 2002</div> </div>		ATTY. DOCKET NO. M122-1680	SERIAL NO. 09/823,664
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT David Hembree	
FILING DATE April 3, 2001				GROUP 2818	

Examiner Initial	Class	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
VW		AA 5,612,574	3/18/97	Sumnerfeld et al.			
		AB 5,719,333	2/17/98	Hosoi et al.			
		AC 5,831,333	11/3/98	Malladi et al.			
		AD 5,919,548	7/6/99	Barron et al.			
		AE 5,351,283	9/2/96	Manaka et al.			
		AF 5,492,011	2/20/96	Amano et al.			
		AG					
		AH					
		AJ					

FOREIGN PATENT DOCUMENTS								
Class	Document Number	Date	Country	Class	Subclass	Translation		
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	AK							
	AL							
	AM							
	AN							

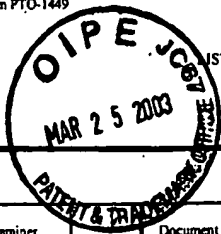
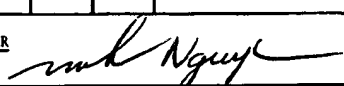
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
VW	AP		"NTC and PTC Thermistors"; <a href="http://www.thermodisc.com/ntcptc.html">http://www.thermodisc.com/ntcptc.html</a> ; 1/7/98; 2 pages.
	AR		"DI-1B33 Linearized 4-Wire RTD Input"; <a href="http://www.dataq.com/d5b33.html">http://www.dataq.com/d5b33.html</a> ; 1/7/98; 2 pages.
	AS		"RTD"; <a href="http://www.mtsensors.com/rtds.html">http://www.mtsensors.com/rtds.html</a> ; 1/7/98; 3 pages.
	AT		"Low Cost Thermal-Ribbon (TM) uses thin film RTD"; <a href="http://www.minco.com/s17624nr.html">http://www.minco.com/s17624nr.html</a> ; 1/7/98; 1 page.
	AU		"Silicon Processing for the VLSI Era"; Volume 1 - Process Technology, Second Edition; S. Wolf et al.; 2000; pps 22-25 and pps. 841-845.

EXAMINER <i>Michael Nguyen</i>	03/12/04
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				LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)			
APPLICANT Micron Technology, Inc.				FILING DATE April 3, 2001		GROUP 2858	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
VN	AA	4,912,600	3/1990	Jaeger et al.	361	700	
↓	AB	5,436,494	7/1995	Moschi	257	467	
↓	AC	5,969,639	10/1999	Lauf et al.	340	870.17	
	AD						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.			
				FILING DATE April 3, 2001		GROUP 2858	
U.S. PATENT DOCUMENTS							
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VN	AA	4,355,463	10/26/1982	Burns			
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EXAMINER <i>mh Nguyen</i>				DATE CONSIDERED 03/12/04			
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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micro Technology, Inc.			
				FILING DATE April 2, 2001		GROUP 2858	
U.S. PATENT DOCUMENTS							
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VN	AA	6,020,750	3/1/2000	Burger et al.			
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	AD						
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